Design Practices for Better Reliability and Yield

Embedded Tutorial

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Thanks to the swift advance of semiconductor technology companies continually do introduce new embedded functions in their integrated circuits. Embedded support functions, such as for Design-for-Testability, have already become traditional. Today, advanced embedded functions, beyond DFT, are being introduced into new designs to enhance the overall reliability of an IC, to contribute to the analysis of its defects, and to help optimize the yield. This embedded tutorial will discuss a variety of advanced design practices meant to improve reliability and yield.